**Suppl. Info.** Significant Joule self-heating pervasive in the emergent thin-film transistor studies. 11 Oct. 2024

## **TABLE: Significant Joule self-heating pervasive in the emergent thin-film transistor studies.**

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**TABLE S1. A few illustrative cases of field-effect transistor (FET) studies of metal-halide perovskites, conjugated polymers, and small-molecule organic semiconductors, where high power density (***P***max) and/or power (***W***max) have been apparently reached in the transistors' channel. Parameters, including the channel width (***W***) and**  length (*L*), the effective source-drain electric field (*E*<sub>DS</sub>), and the maximum source-drain current (|*I*<sub>DS</sub>|<sup>max</sup>), are **also listed, along with the studied material and the corresponding Figure.** 

 $E_{DS}$  is the effective longitudinal (source-drain) electric field in a FET channel applied during the recording of transfer curves corresponding to the extracted  $W_{\text{max}}$  and  $P_{\text{max}}$ , defined as  $E_{\text{DS}} = |V_{\text{DS}}|/L$ , where  $V_{\text{DS}}$  is the source-drain voltage applied during the measurement, and *L* is the channel length.

*W***max** is the maximum apparent electric power dissipated in the channel of the reported FET, calculated from the corresponding transfer curve as  $W_{\text{max}} \equiv |I_{\text{DS}}|^{\text{max}} \cdot |V_{\text{DS}}|$ .

 $P_{\text{max}}$  is the corresponding maximum apparent electric power density emitted in the channel, calculated from the reported transfer curve as  $P_{\text{max}} \equiv |I_{\text{DS}}|^{\text{max}} \cdot |V_{\text{DS}}| / (LW)$ .

For the control experiment on infra-red imaging of the surface temperature distribution of biased devices, emulating specific experimental conditions used in Ref. [1], see Supplementary video (a separate file).

#	Reference	semiconductor	Fig.	W $(\mu m)$	L $(\mu m)$	$ I_{DS} ^{max}$ (A)	<b>E</b> <sub>ps</sub> $(kV cm^{-1})$	W <sub>max</sub> (M)	$P_{\text{max}}$ $(Wcm2)*$
1	H. Zhu et al., Nat. Electron. $(2023)^1$	Hybrid tin halide perovskite, $(Cs_xFA_{1-x})PEA_2Sn_8I_{25}$ $x = 10\%)$	1 <sub>c</sub>	1000	200	0.01	$\overline{2}$	0.4	200
$\overline{2}$	A. Liu et al., Nat. Electron. (2022) <sup>2</sup>	Tin halide perovskite, CsSnl <sub>3</sub>	1 <sub>d</sub>	1000	150	$6.8 \times 10^{-3}$	2.67	0.27	181
3	W. Yang et al., Adv. Mater. (2024) <sup>3</sup>	Hybrid tin halide perovskite, FASnI3 with F- PEAI	3i	1000	100	$9\times10^{-3}$	4	0.36	361
4	F. Yang et al., Org. Electron. (2016) <sup>4</sup>	Conj. polymer, P2MDPP2T- DTT	2c	1400	40	$4.23 \times 10^{-3}$	25	0.42	755
5	Y. Ji et al., Adv. Mater. (2016) <sup>5</sup>	Conj. polymer, PDPPMT-2T	2c	1400	40	$4\times10^{-3}$	25	0.4	709

**<sup>\*</sup> For comparison:** 

 $\overline{a}$ 

**<sup>(</sup>a) The working surface of a typical household clothes iron emits about 0.36 Wcm-2 at full-power operation.** 

**<sup>(</sup>b) The integral power density emitted by the Sun at its surface is ~ 6.4 kW·cm-2 .** 

**<sup>(</sup>c) The power density of a CO<sup>2</sup> laser beam in industrial laser cutting machines for plastics, wood and leather is 3 - 10 kW·cm-2 .** 



For the analysis of FET mobilities and the corresponding mobility reliability factors in some of these papers, see Refs. [18-21].

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